NVMFD5489NL

MOSFET – Power, Dual N-Channel, Logic Level
60 V, 65 mΩ, 12 A

ON Semiconductor®

Features

- Small Footprint (5x6 mm) for Compact Designs
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- 175°C Operating Temperature
- NVMFD5489NLWF – Wettable Flank Option for Enhanced Optical Inspection
- AEC−Q101 Qualified and PPAP Capable
- This is a Pb−Free Device

$V_{(BR)DSS}$	$R_{DS(on)}$ MAX	I_D MAX
60 V	65 mΩ @ 10 V	12 A
	79 mΩ @ 4.5 V	

Dual N−Channel

MARKING DIAGRAM

DFN8 5x6
(SO8FL)
CASE 506BT

XXXXXX = 5489NL
          (NVMFD5489NL) or
          5489LW
          (NVMFD5489NLWF)
A   = Assembly Location
Y   = Year
W   = Work Week
ZZ = Lot Traceability

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit
Drain−to−Source Voltage		V_{DSS}	60	V
Gate−to−Source Voltage		V_{GS}	±20	V
Continuous Drain Current $R_{\Psi J-mb}$ (Notes 1, 2, 3, 4)	Steady State — T_{mb} = 25°C	I_D	12	A
	T_{mb} = 100°C		8.8	
Power Dissipation $R_{\Psi J-mb}$ (Notes 1, 2, 3)	T_{mb} = 25°C	P_D	23.4	W
	T_{mb} = 100°C		11.7	
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 3 & 4)	Steady State — T_A = 25°C	I_D	4.5	A
	T_A = 100°C		3.2	
Power Dissipation $R_{\theta JA}$ (Notes 1 & 3)	T_A = 25°C	P_D	3.0	W
	T_A = 100°C		1.5	
Pulsed Drain Current	T_A = 25°C, t_p = 10 μs	I_{DM}	62	A
Operating Junction and Storage Temperature		T_J, T_{stg}	−55 to 175	°C
Source Current (Body Diode)		I_S	22	A
Single Pulse Drain−to−Source Avalanche Energy (T_J = 25°C, $I_{L(pk)}$ = 19.5 A, L = 0.1 mH, R_G = 25 Ω)		E_{AS}	19	mJ
Lead Temperature for Soldering Purposes (1/8″ from case for 10 s)		T_L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
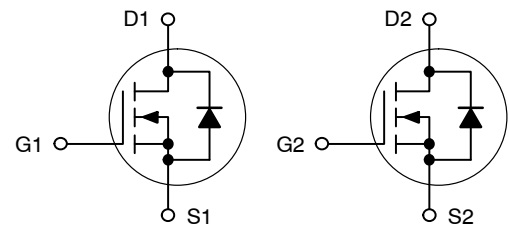
THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction−to−Mounting Board (top) − Steady State (Notes 2, 3)	$R_{\Psi J-mb}$	6.4	
Junction−to−Ambient − Steady State (Note 3)	$R_{\theta JA}$	50	°C/W
Junction−to−Ambient − Steady State (min footprint)		161	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Psi (Ψ) is used as required per JESD51−12 for packages in which substantially less than 100% of the heat flows to single case surface.
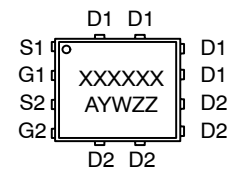
ORDERING INFORMATION

Device	Package	Shipping[†]
NVMFD5489NLT1G	DFN8 (Pb−Free)	1500/ Tape & Reel
NVMFD5489NLT3G	DFN8 (Pb−Free)	5000/ Tape & Reel
NVMFD5489NLWFT1G	DFN8 (Pb−Free)	1500/ Tape & Reel
NVMFD5489NLWFT3G	DFN8 (Pb−Free)	5000/ Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

July, 2019 – Rev. 3

3. Surface−mounted on FR4 board using a 650 mm^2, 2 oz. Cu pad.
4. Continuous DC current rating. Maximum current for pulses as long as 1 second are higher but are dependent on pulse duration and duty cycle.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Typ	Max	Unit
OFF CHARACTERISTICS							
Drain−to−Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0 V, I_D = 250 μA		60			V
Drain−to−Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$	Reference to 25°C I_D = 250 μA			67		mV/°C
Zero Gate Voltage Drain Current	I_{DSS}	V_{GS} = 0 V, V_{DS} = 60 V	T_J = 25°C			1.0	μA
			T_J = 125°C			10	
Gate−to−Source Leakage Current	I_{GSS}	V_{DS} = 0 V, V_{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	$V_{GS(TH)}$	V_{GS} = V_{DS}, I_D = 250 μA		1.5		2.5	V
Negative Threshold Temperature Co-efficient	$V_{GS(TH)}/T_J$	Reference to 25°C I_D = 250 μA			4.86		mV/°C
Drain−to−Source On Resistance	$R_{DS(on)}$	V_{GS} = 10 V, I_D = 15 A			52	65	mΩ
		V_{GS} = 4.5 V, I_D = 7.5 A			66	79	
CHARGES AND CAPACITANCES							
Input Capacitance	C_{iss}	V_{GS} = 0 V, f = 1.0 MHz, V_{DS} = 25 V			330		pF
Output Capacitance	C_{oss}				80		
Reverse Transfer Capacitance	C_{rss}				39		
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = 10 V, V_{DS} = 48 V, I_D = 6 A			12.4		nC
Threshold Gate Charge	$Q_{G(TH)}$				0.31		
Gate−to−Source Charge	Q_{GS}				1.3		
Gate−to−Drain Charge	Q_{GD}				4.74		
SWITCHING CHARACTERISTICS (Note 6)							
Turn−On Delay Time	$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 48 V, I_D = 6 A, R_G = 2.5 Ω			7		ns
Rise Time	t_r				11		
Turn−Off Delay Time	$t_{d(off)}$				31		
Fall Time	t_f				21		
DRAIN−SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V_{SD}	V_{GS} = 0 V, I_S = 10 A	T_J = 25°C		0.83	1.2	V
			T_J = 125°C		0.71		
Reverse Recovery Time	t_{RR}	V_{GS} = 0 V, d_{IS}/d_t = 100 A/μs, I_S = 10 A			24.2		ns
Charge Time	t_a				20.2		
Discharge Time	t_b				4.0		
Reverse Recovery Charge	Q_{RR}				26.5		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L_S	T_A = 25°C			0.93		nH
Drain Inductance	L_D				0.005		
Gate Inductance	L_G				1.84		
Gate Resistance	R_G				12		Ω

5. Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.
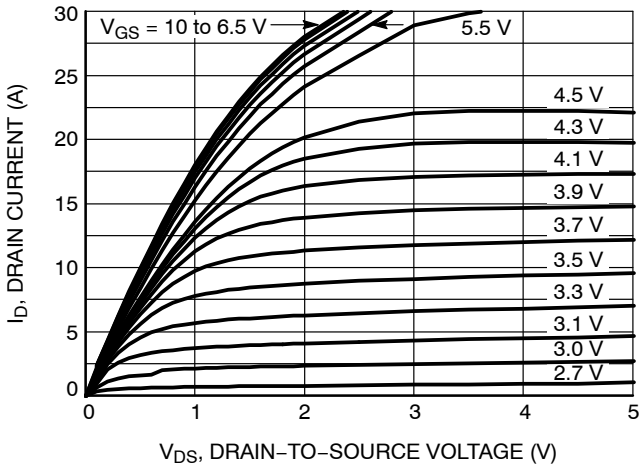
TYPICAL CHARACTERISTICS
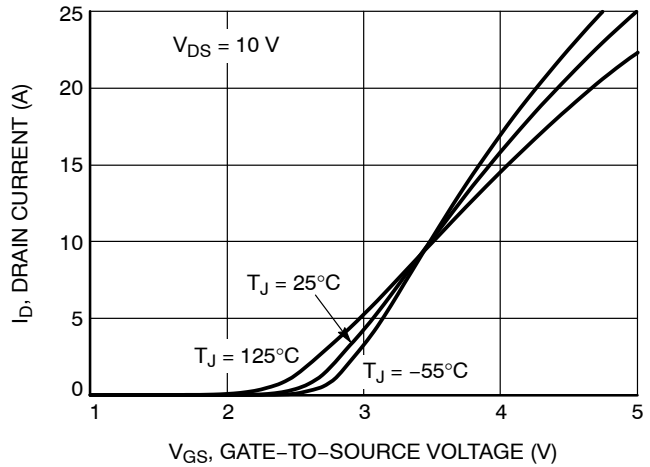

Figure 1. On−Region Characteristics
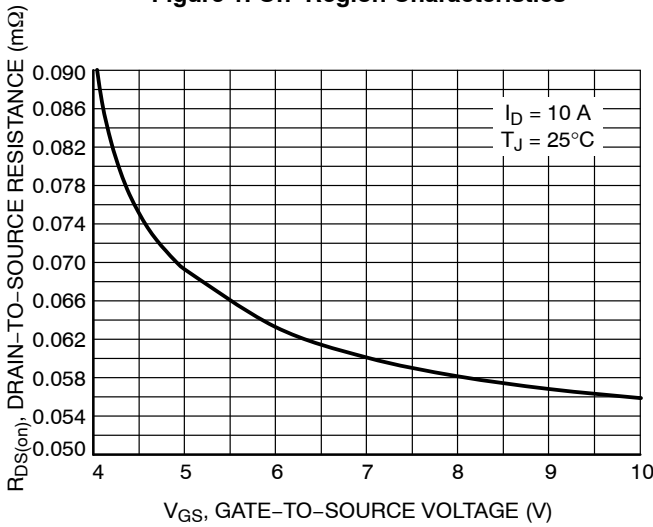

Figure 2. Transfer Characteristics

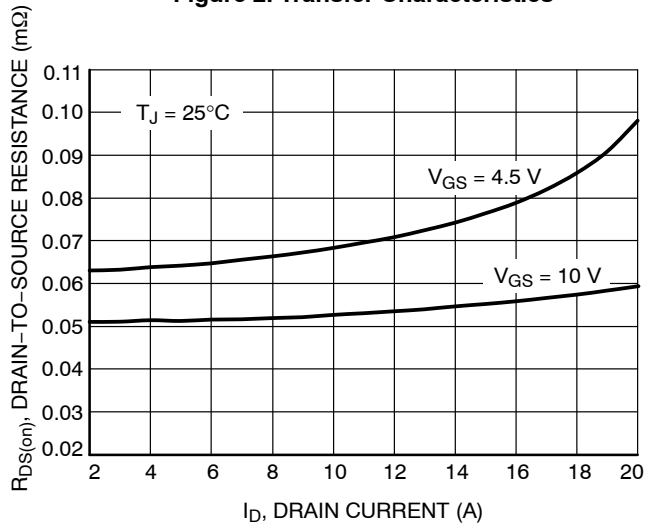**Figure 3. On−Resistance vs. V$_{GS}$**

Figure 4. On−Resistance vs. Drain Current and Gate Voltage
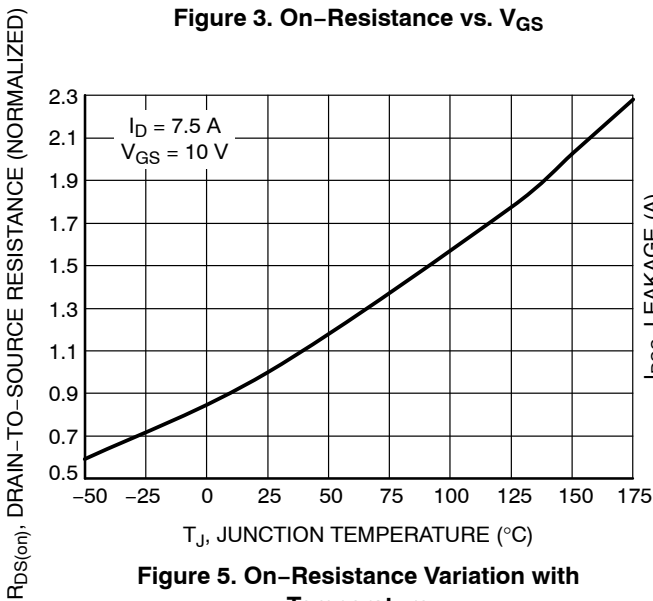

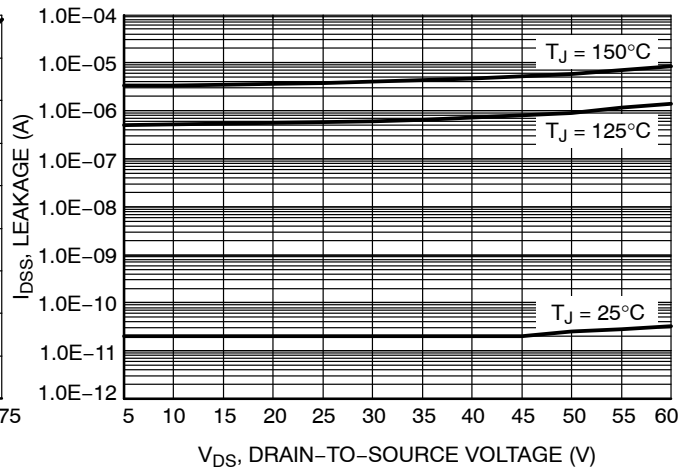**Figure 5. On−Resistance Variation with Temperature**

Figure 6. Drain−to−Source Leakage Current vs. Voltage
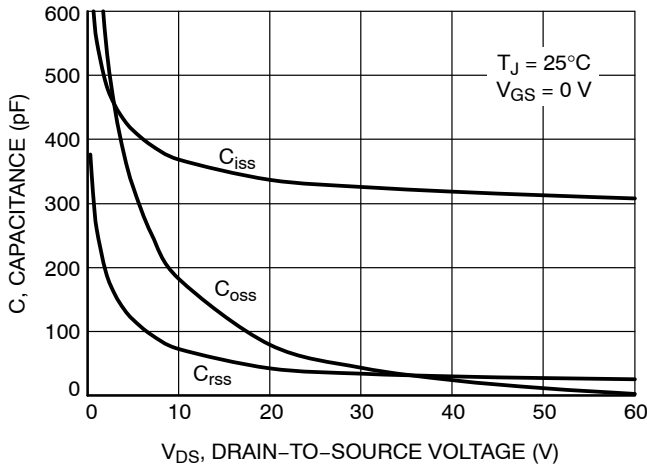
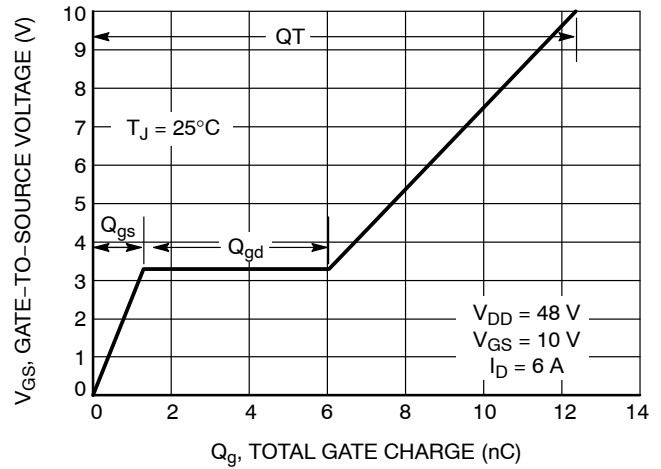## TYPICAL CHARACTERISTICS

Figure 7. Capacitance Variation

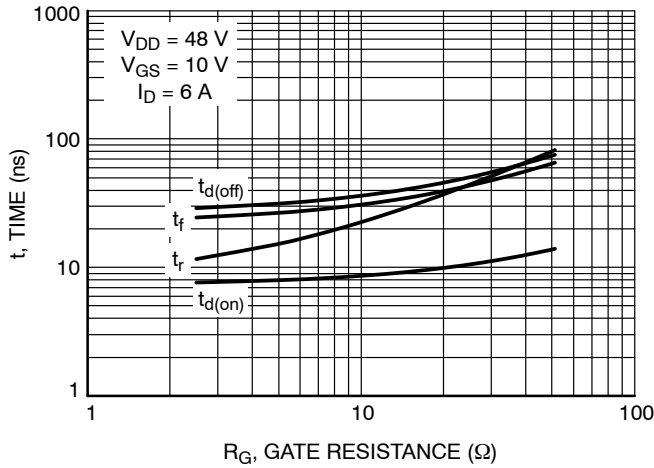**Figure 8. Gate–to–Source and Drain–to–Source Voltage vs. Total Charge**

Figure 9. Resistive Switching Time Variation vs. Gate Resistance
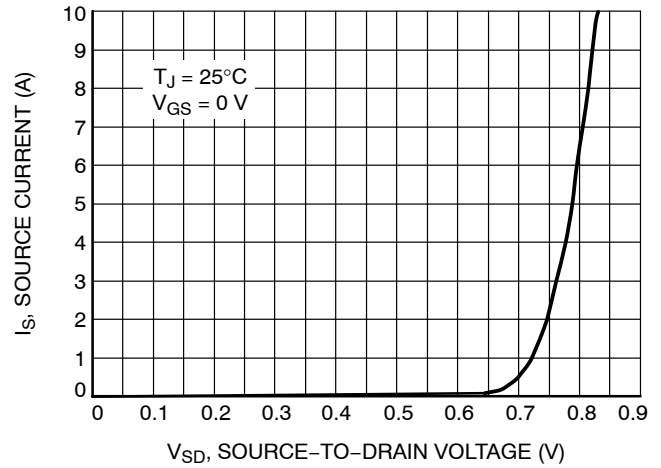
Figure 10. Diode Forward Voltage vs. Current
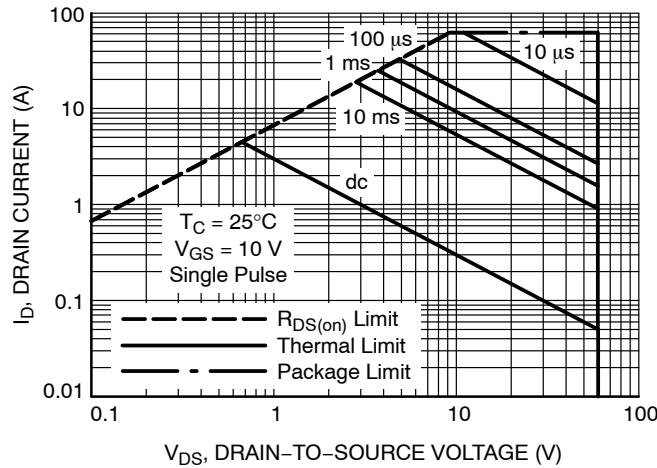
Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS
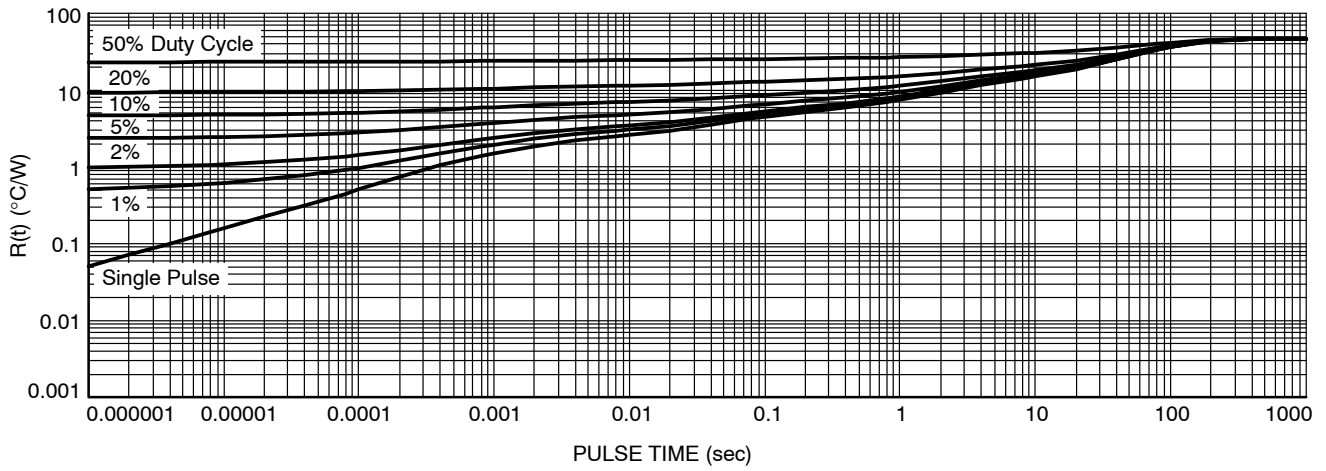
Figure 12. Thermal Response

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

ON Semiconductor®
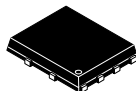
DFN8 5x6, 1.27P Dual Flag (SO8FL–Dual)
CASE 506BT
ISSUE E

DATE 26 FEB 2013

SCALE 2:1

2X
⌒ | 0.20 | C

D → A

D1

B | 2X
⌒ | 0.20 | C

8 7 6 5

PIN ONE
IDENTIFIER
NOTE 7

E1 | E

1 2 3 4

TOP VIEW

4X
h

c

A1

DETAIL A

// | 0.10 | C

⌒ | 0.10 | C

NOTE 4

A

SIDE VIEW

DETAIL A

C | SEATING
PLANE
NOTE 6

D2

D3

e

4X L

1 4

K

DETAIL B

DETAIL B
ALTERNATE
CONSTRUCTION

N

M

4X
b1

E2

8 5

4X G

8X b

K1

8X b

⊕ | 0.10 | C | A | B
| 0.05 | C | NOTE 3

BOTTOM VIEW
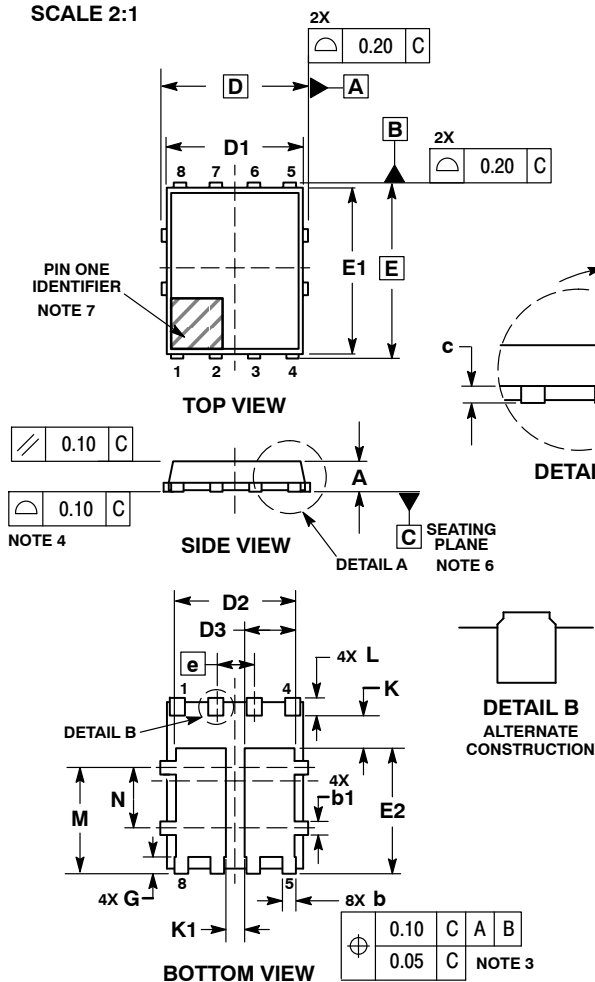
NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30 MM FROM THE TERMINAL TIP.
4. PROFILE TOLERANCE APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
5. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
6. SEATING PLANE IS DEFINED BY THE TERMINALS. A1 IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
7. A VISUAL INDICATOR FOR PIN 1 MUST BE LOCATED IN THIS AREA.

GENERIC MARKING DIAGRAM*

1
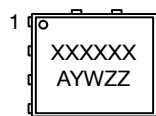
XXXXXX
AYWZZ

XXXXXX = Specific Device Code
A = Assembly Location
Y = Year
W = Work Week
ZZ = Lot Traceability

*This information is generic. Please refer to device data sheet for actual part marking.

DIM	MILLIMETERS		
	MIN	MAX	MAX
A	0.90	---	1.10
A1	---	---	0.05
b	0.33	0.42	0.51
b1	0.33	0.42	0.51
c	0.20	---	0.33
D	5.15 BSC		
D1	4.70	4.90	5.10
D2	3.90	4.10	4.30
D3	1.50	1.70	1.90
E	6.15 BSC		
E1	5.70	5.90	6.10
E2	3.90	4.15	4.40
e	1.27 BSC		
G	0.45	0.55	0.65
h	---	---	12 °
K	0.51	---	---
K1	0.56	---	---
L	0.48	0.61	0.71
M	3.25	3.50	3.75
N	1.80	2.00	2.20

SOLDERING FOOTPRINT*

4.56

8X
0.75

2X
2.08

2X
0.56

4.84

2.30

4X
1.40

3.70

6.59

0.70

4X 1.00

1.27
PITCH

5.55
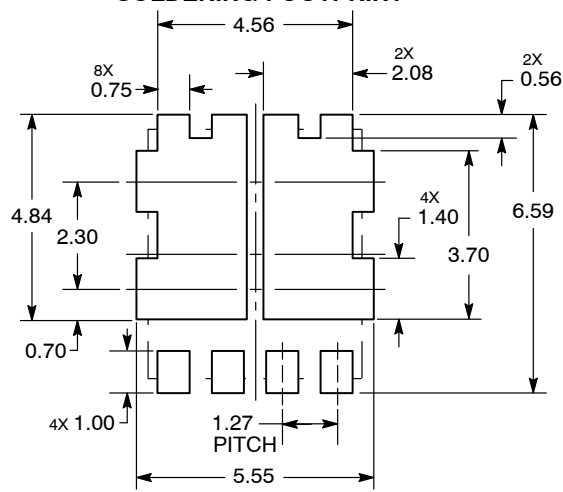
DIMENSION: MILLIMETERS

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	**DFN8 5X6, 1.27P DUAL FLAG (SO8FL–DUAL)**		**PAGE 1 OF 1**

PUBLICATION ORDERING INFORMATION

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